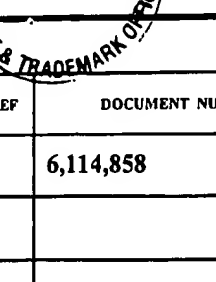



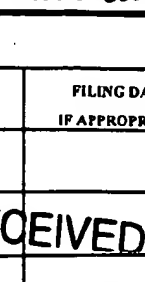
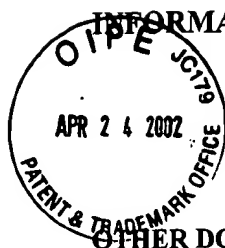


<div style="display: flex; justify-content: space-between; align-items: center;"> <div style="text-align: center;">  </div> <div> INFORMATION DISCLOSURE CITATION (Use several sheets if necessary) </div> </div>				Docket Number (Optional) P 6079:11005		Application Number 09/837,887		
				Applicant(s) Voorakaranam et al.		Filing Date April 18, 2001		Group Art Unit 2858-2857
U.S. PATENT DOCUMENTS								
EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
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EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								



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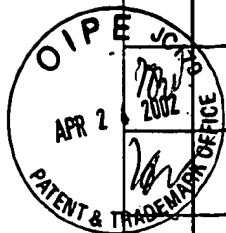
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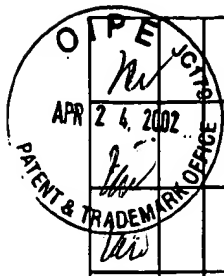
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